EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	2316	(438/14).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/21 11:36
L2	399	1 and (inspect$4 evaluat$4 monitor$4 analyz$4 scan$4) with (defect flaw deficiency imperfection)	US-PGPUB; USPAT	OR	ON	2006/12/21 11:36
L3	293	2 and (classif$4 sort$4 allocat$4 arrang$4 distribut$4 match$4 organiz$4 segregat$4)	US-PGPUB; USPAT	OR	ON	2006/12/21 11:37
L4	35	3 and (classif$4 sort$4 allocat$4 arrang$4 distribut$4 match$4 organiz$4 segregat$4) with (defect flaw deficiency imperfection) with (size dimension proportion)	US-PGPUB; USPAT	OR	ON	2006/12/21 13:06
L5	12	(257/e21.529).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/21 13:07
L6	1	(257/e21.529).CCLS.	EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2006/12/21 13:07
S1	1	(("5,544,256") or ("6,373,566B2")).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/21 11:36
S2	2	(("5,544,256") or ("6,373,566")).PN.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/19 08:14
S3	4	anisotropic adj sampling	US-PGPUB; USPAT	OR	ON	2006/12/19 08:20
S4	5592	(substrate or wafer) with (inspect$4 evaluat$4 monitor$4 analyz$4 scan$4) with (defect flaw deficiency imperfection)	US-PGPUB; USPAT	OR	ON	2006/12/21 11:36
S5	4627	S4 and (classif$4 sort$4 allocat$4 arrang$4 distribut$4 match$4 organiz$4 segregat$4)	US-PGPUB; USPAT	OR	ON	2006/12/21 11:37
S6	2103	S4 and (classif$4 sort$4 allocat$4 arrang$4 distribut$4 match$4 organiz$4 segregat$4) with (defect flaw deficiency imperfection)	US-PGPUB; USPAT	OR	ON	2006/12/19 08:27
S7	499	S4 and (classif$4 sort$4 allocat$4 arrang$4 distribut$4 match$4 organiz$4 segregat$4) with (defect flaw deficiency imperfection) with (size dimension proportion)	US-PGPUB; USPAT	OR	ON	2006/12/21 11:37

EAST Search History

S8	499	S4 and (classif$4 sort$4 allocat$4 arrang$4 distribut$4 match$4 organiz$4 segregat$4) with (defect flaw deficiency imperfection) with (size dimension proportion)	US-PGPUB; USPAT	OR	ON	2006/12/19 08:46
S9	1050	S4 and (size dimension proportion) with (range ambit amplitude bound confines span spread)	US-PGPUB; USPAT	OR	ON	2006/12/19 08:41
S10	180	S8 and (size dimension proportion) with (range ambit amplitude bound confines span spread)	US-PGPUB; USPAT	OR	ON	2006/12/19 08:43
S11	0	S10 and (group collection accumulation assemblage conglomerate pool) with (upper) with (range ambit amplitude bound confines span spread)	US-PGPUB; USPAT	OR	ON	2006/12/19 08:47
S12	23	S10 and (group collection accumulation assemblage conglomerate pool) with (ratio proportion proportionality relationship relation)	US-PGPUB; USPAT	OR	ON	2006/12/19 11:17
S13	107	("5103557" | "5210041" | "5219765" | "5240866" | "5286656" | "5360747" | "5440649" | "5475766" | "5544256" | "5598341" | "5665609").PN. OR ("5991699").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/19 10:45
S14	1	("5801965").PN. OR ("7113628"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/19 10:46
S15	8	S8 and monotonically	US-PGPUB; USPAT	OR	ON	2006/12/19 11:18
S16	3816	((702/33) or (702/35) or (702/117) or (702/118) or (702/119) or (702/120) or (702/83) or (356/628) or (356/625) or (356/237.1)).CCLS.	US-PGPUB; USPAT; USOCR	OR	OFF	2006/12/19 11:18
S17	289	S16 and ((substrate or wafer) with (inspect$4 evaluat$4 monitor$4 analyz$4 scan$4) with (defect flaw deficiency imperfection))	US-PGPUB; USPAT	OR	ON	2006/12/19 11:19
S18	234	S17 and size	US-PGPUB; USPAT	OR	ON	2006/12/19 11:19
S19	22	S17 and (group$4 with size)	US-PGPUB; USPAT	OR	ON	2006/12/19 11:19
S20	20	("5936726").PN. OR ("6157444"). URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/12/19 11:34